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• FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: June 12, 2002				ATTY DOCKET NO. 2001-1897 APPLICANT Makoto AKIZUKI et al. FILING DATE December 26, 2001 U.S. PATENT DOCUMENTS																	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted to PTO: December 26, 2001					ATTY DOCKET NO. SERIAL 2001-1897 -NEW-			NO. 10 1025 899			
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